

V_{DSM} = 6500 V
 I_{TAVM} = 1800 A
 I_{TRMS} = 2820 A
 I_{TSM} = 32000 A
 V_{TO} = 1.20 V
 r_T = 0.430 mW

Phase Control Thyristor

5STP 18M6500

Doc. No. 5SYA1010-03 Aug.00

- Patented free-floating silicon technology
- Low on-state and switching losses
- Designed for traction, energy and industrial applications
- Optimum power handling capability
- Interdigitated amplifying gate.

Blocking

Part Number	5STP 18M6500	5STP 18M6200	5STP 18M5800	Conditions
V_{DSM} V_{RSM}	6500 V	6200 V	5800 V	$f = 5 \text{ Hz}, t_p = 10\text{ms}$
V_{DRM} V_{RRM}	5600 V	5300 V	4900 V	$f = 50 \text{ Hz}, t_p = 10\text{ms}$
V_{RSM1}	7000 V	6700 V	6300 V	$t_p = 5 \text{ ms, single pulse}$
I_{DSM}	$\leq 600 \text{ mA}$			V_{DSM}
I_{RSM}	$\leq 600 \text{ mA}$			V_{RSM}
dV/dt_{crit}		2000 V/ μs	@ Exp. to 0.67x V_{DRM}	$T_j = 125^\circ\text{C}$

V_{DRM}/V_{RRM} are equal to V_{DSM}/V_{RSM} values up to $T_j = 110^\circ\text{C}$

Mechanical data

F_M	Mounting force	nom.	70 kN
		min.	63 kN
		max.	84 kN
a	Acceleration		
	Device unclamped		50 m/s ²
	Device clamped		100 m/s ²
m	Weight		1.85 kg
D _S	Surface creepage distance		45 mm
D _a	Air strike distance		21 mm

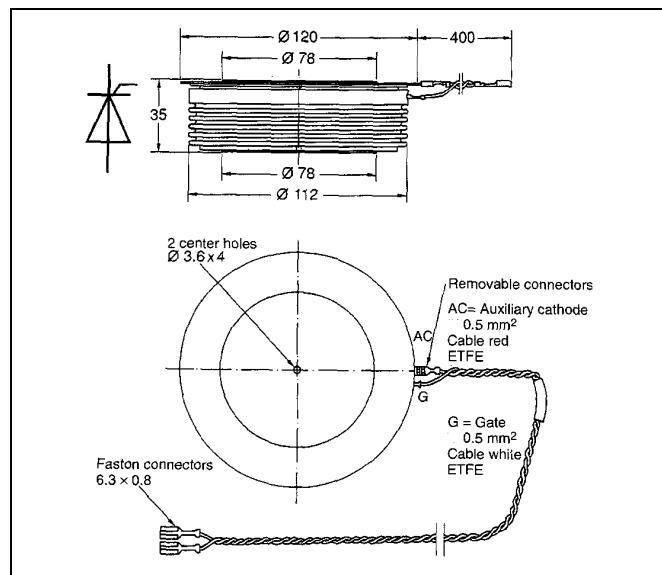


ABB Semiconductors AG reserves the right to change specifications without notice.

On-state

I_{TAVM}	Max. average on-state current	1800 A	Half sine wave, $T_C = 70^\circ\text{C}$	
I_{TRMS}	Max. RMS on-state current	2820 A		
I_{TSM}	Max. peak non-repetitive surge current	32000 A	$tp = 10 \text{ ms}$	$T_j = 125^\circ\text{C}$
		35000 A	$tp = 8.3 \text{ ms}$	After surge:
I^2t	Limiting load integral	5120 kA^2s	$tp = 10 \text{ ms}$	$V_D = V_R = 0\text{V}$
		5000 kA^2s	$tp = 8.3 \text{ ms}$	
V_T	On-state voltage	1.90 V	$I_T = 1600 \text{ A}$	$T_j = 125^\circ\text{C}$
V_{T0}	Threshold voltage	1.20 V	$I_T = 1000 - 3000 \text{ A}$	
r_T	Slope resistance	0.430 $\text{m}\Omega$		
I_H	Holding current	50-125 mA	$T_j = 25^\circ\text{C}$	
		20-75 mA	$T_j = 125^\circ\text{C}$	
I_L	Latching current	100-500 mA	$T_j = 25^\circ\text{C}$	
		75-250 mA	$T_j = 125^\circ\text{C}$	

Switching

di/dt_{crit}	Critical rate of rise of on-state current	250 A/ μs	Cont.	$V_D \leq 0.67 \cdot V_{DRM}$ $T_j = 125^\circ\text{C}$
		500 A/ μs	60 sec.	$I_{TRM} = 2000 \text{ A}$ $f = 50 \text{ Hz}$ $I_{FG} = 2.0 \text{ A}$ $t_r = 0.5 \mu\text{s}$
t_d	Delay time	$\leq 3.0 \mu\text{s}$	$V_D = 0.4 \cdot V_{DRM}$	$I_{FG} = 2.0 \text{ A}$ $t_r = 0.5 \mu\text{s}$
t_q	Turn-off time	$\leq 800 \mu\text{s}$	$V_D \leq 0.67 \cdot V_{DRM}$ $dv_D/dt = 20 \text{ V}/\mu\text{s}$	$I_{TRM} = 2000 \text{ A}$ $T_j = 125^\circ\text{C}$ $V_R > 200 \text{ V}$
Q_{rr}	Recovery charge	min	2000 μAs	$di_T/dt = -1 \text{ A}/\mu\text{s}$
		max	3000 μAs	

Triggering

V_{GT}	Gate trigger voltage	2.6 V	$T_j = 25^\circ\text{C}$
I_{GT}	Gate trigger current	400 mA	$T_j = 25^\circ\text{C}$
V_{GD}	Gate non-trigger voltage	0.3 V	$V_D = 0.4 \cdot V_{DRM}$
I_{GD}	Gate non-trigger current	10 mA	$V_D = 0.4 \cdot V_{DRM}$
V_{FGM}	Peak forward gate voltage	12 V	
I_{FGM}	Peak forward gate current	10 A	
V_{RGM}	Peak reverse gate voltage	10 V	
P_G	Maximum gate power loss	3 W	

Thermal

$T_{j\max}$	Max. junction temperature	125°C	
$T_{j\text{stg}}$	Storage temperature range	-40...150°C	
R_{thJC}	Thermal resistance junction to case	18 K/kW	Anode side cooled
		18 K/kW	Cathode side cooled
		9 K/kW	Double side cooled
R_{thCH}	Thermal resistance case to heat sink	3 K/kW	Single side cooled
		1.5 K/kW	Double side cooled

Analytical function for transient thermal impedance:

$$Z_{\text{thJC}}(t) = \sum_{i=1}^n R_i (1 - e^{-t/t_i})$$

i	1	2	3	4
$R_i(\text{K/kW})$	6.28	1.07	1.09	0.52
$t_i(\text{s})$	0.8956	0.1606	0.0256	0.0093

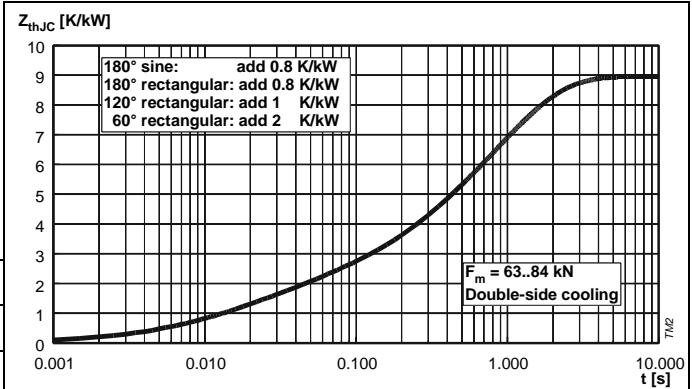


Fig. 1 Transient thermal impedance junction to case.

On-state characteristic model:

$$V_T = A + B \cdot i_T + C \cdot \ln(i_T + 1) + D \cdot \sqrt{i_T}$$

Valid for $i_T = 400 - 6000 \text{ A}$

A	B	C	D
0.871422	0.000093	-0.020798	0.025657

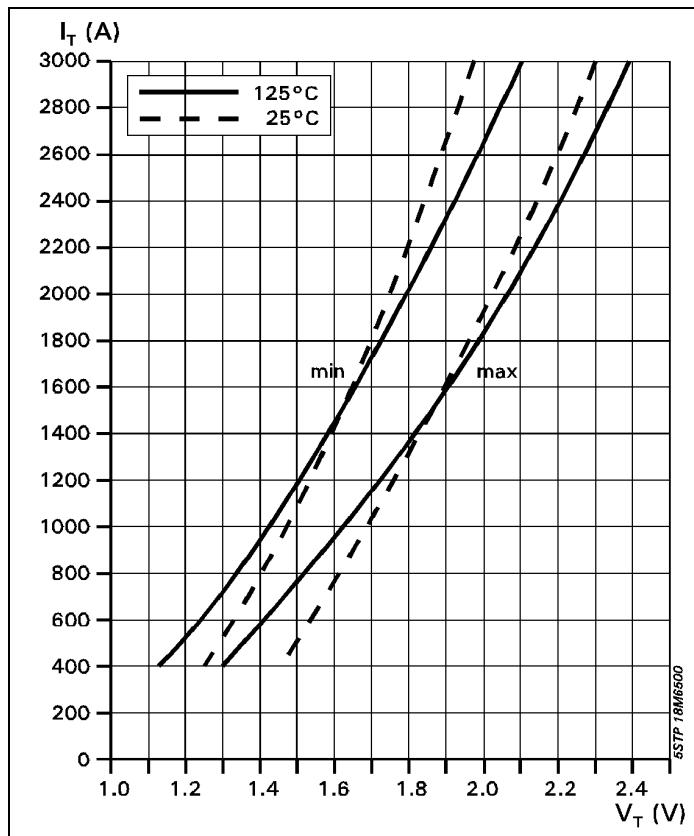


Fig. 2. On-state characteristics.

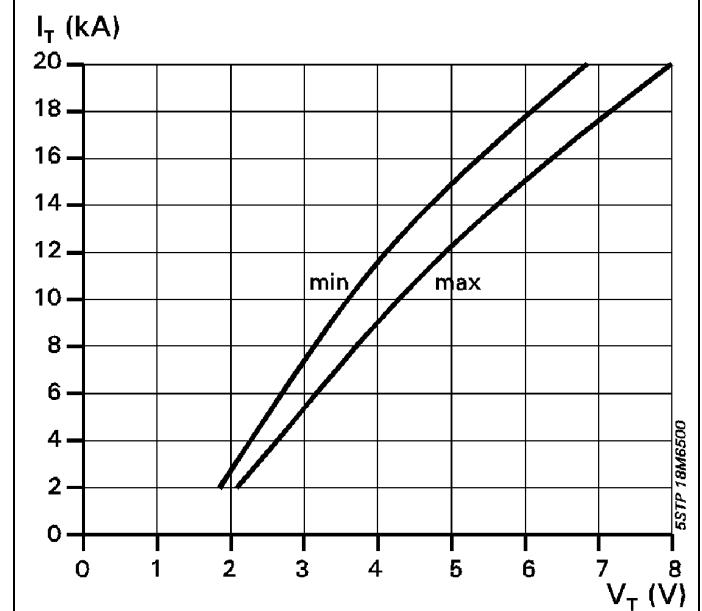
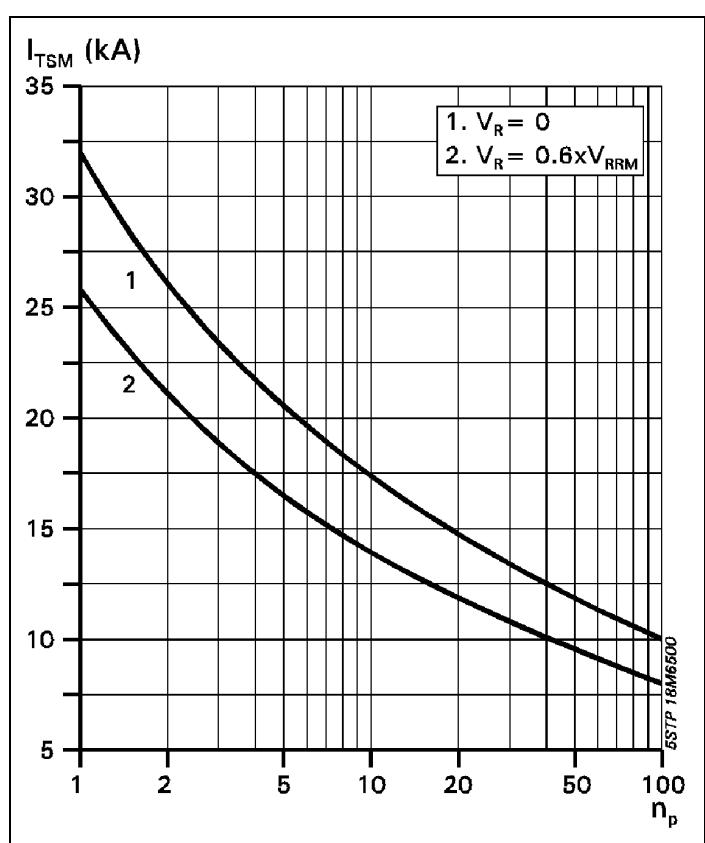
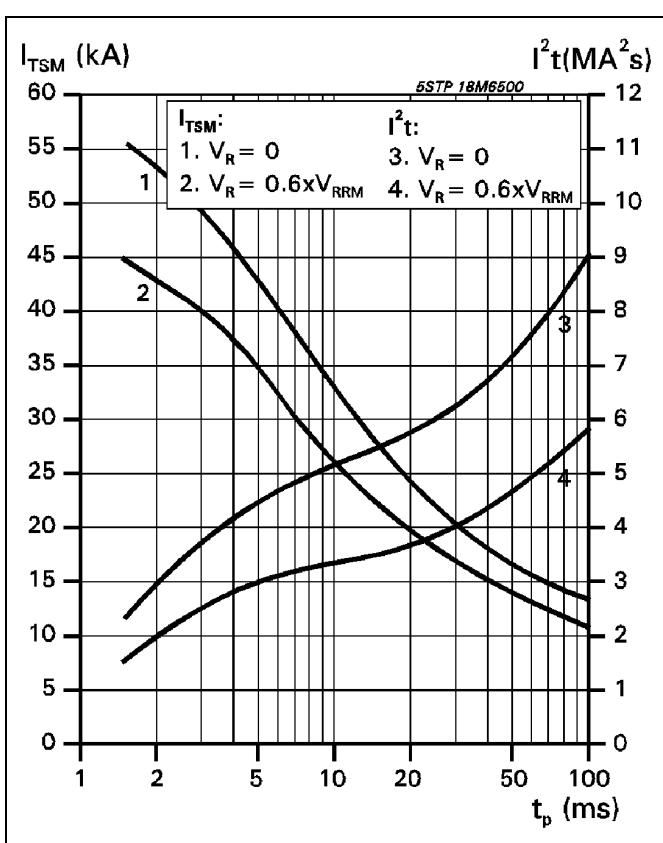
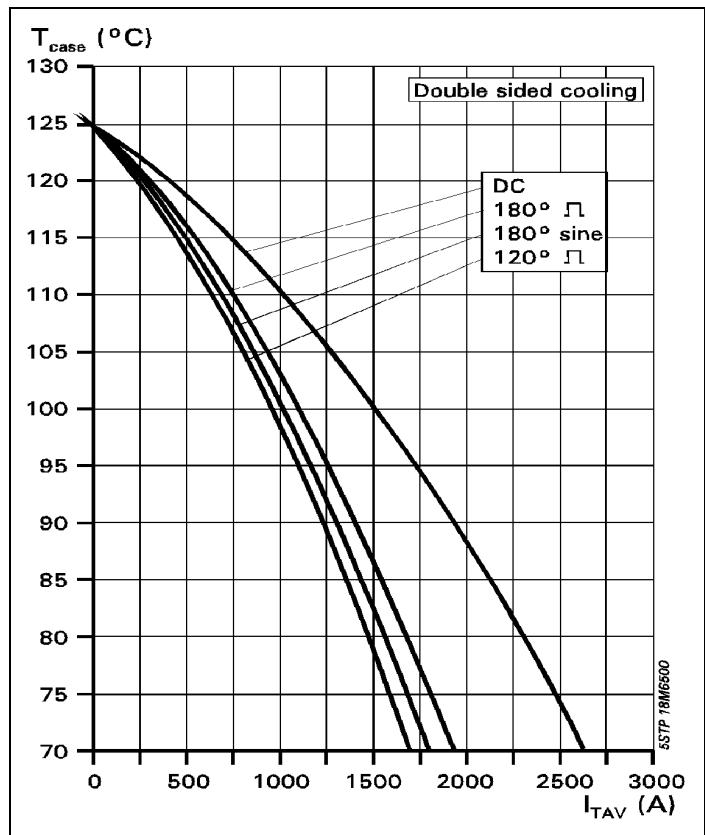
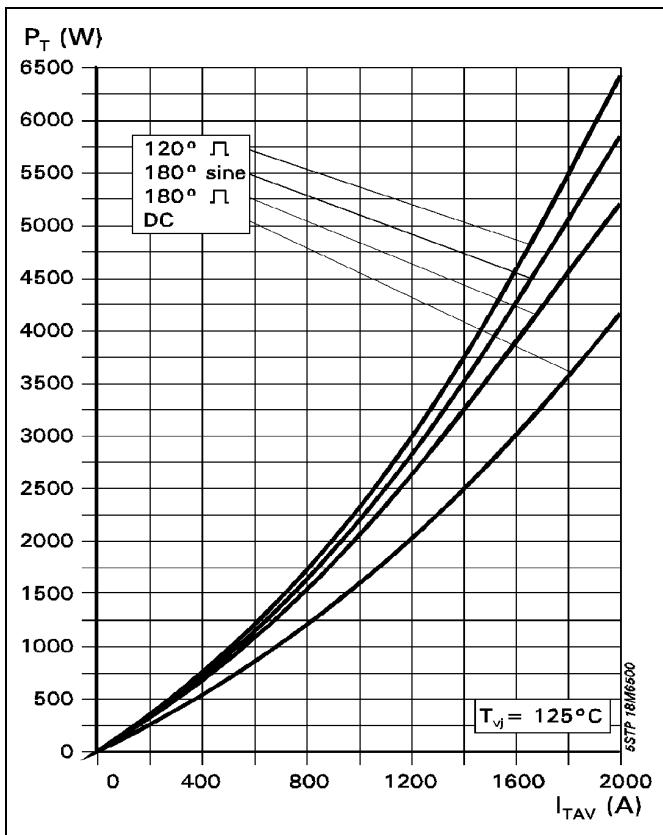


Fig. 3 On state characteristics.



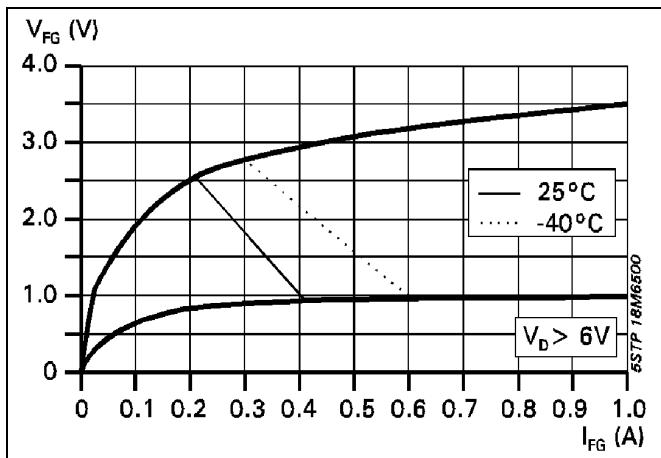


Fig. 8 Gate trigger characteristics.

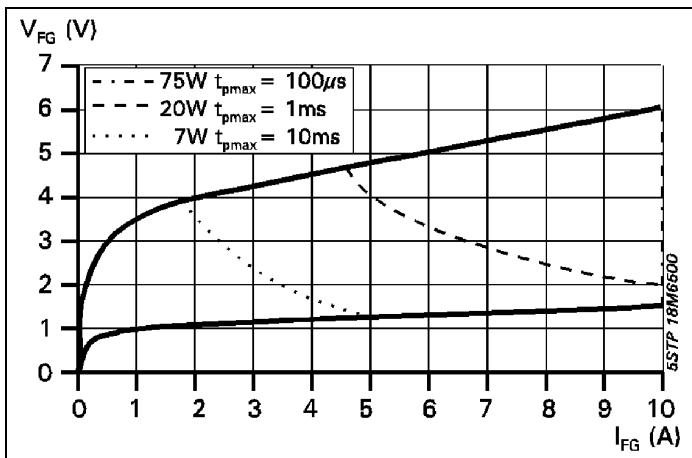


Fig. 9 Max. peak gate power loss.

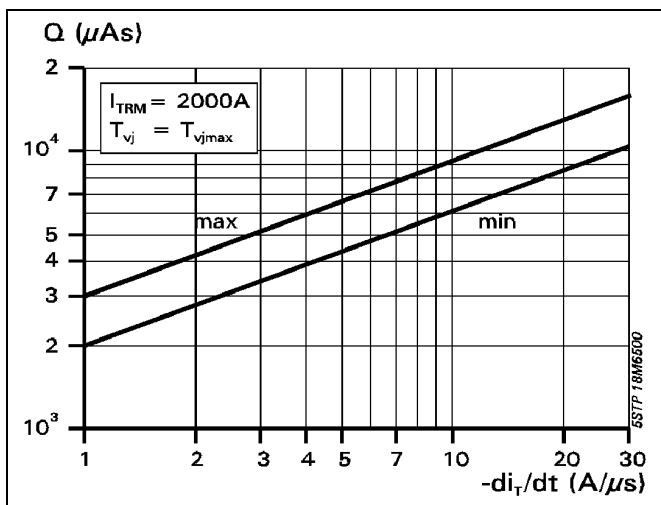


Fig. 10 Recovery charge vs. decay rate of on-state current.

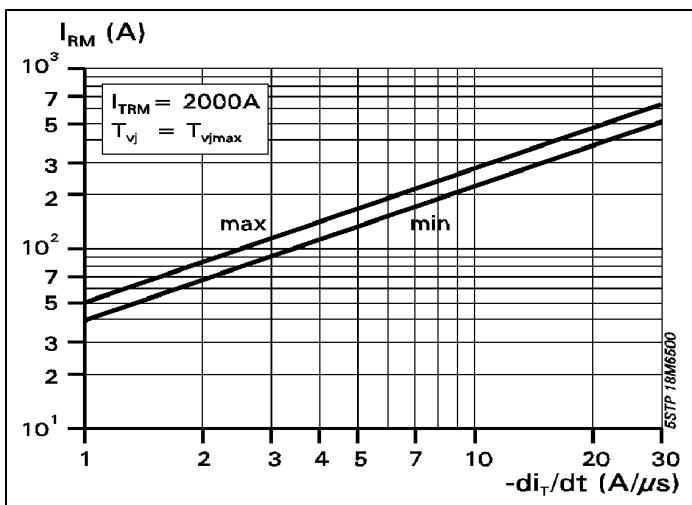
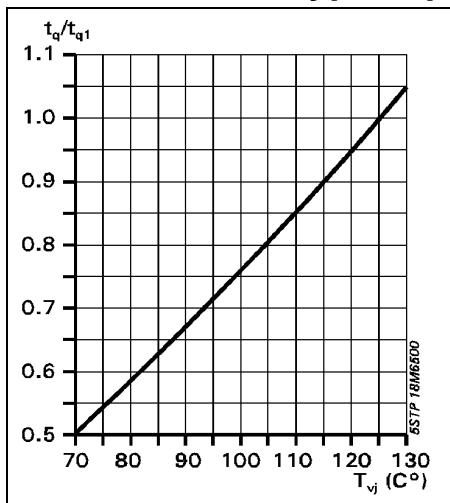
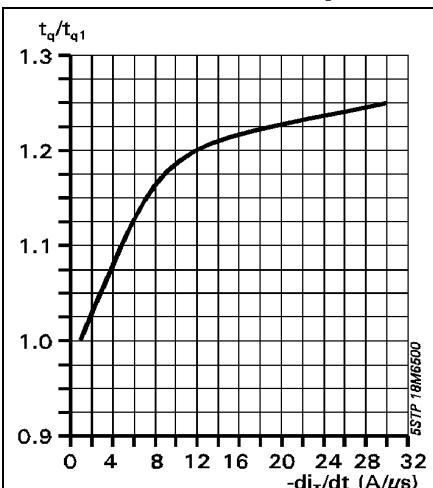
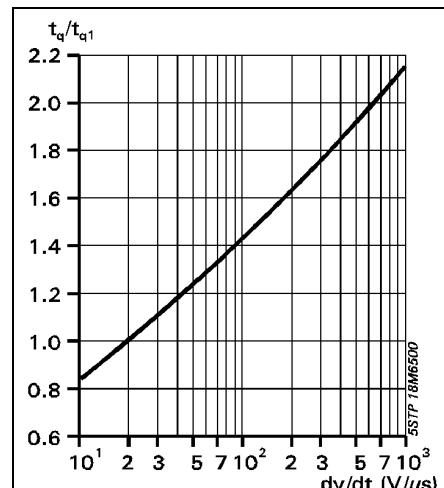


Fig. 11 Peak reverse recovery current vs. decay rate of on-state current.

Turn-off time, typical parameter relationship.

Fig. 12 $t_q/t_{q1} = f_1(T_j)$ Fig. 13 $t_q/t_{q1} = f_2(-di/dt)$ Fig. 14 $t_q/t_{q1} = f_3(dv/dt)$

$$t_q = t_{q1} \cdot t_{q/t_{q1}} f_1(T_j) \cdot t_{q/t_{q1}} f_2(-di/dt) \cdot t_{q/t_{q1}} f_3(dv/dt)$$

t_{q1} : at normalized values (see page 2)

t_q : at varying conditions

Turn-on and Turn-off losses

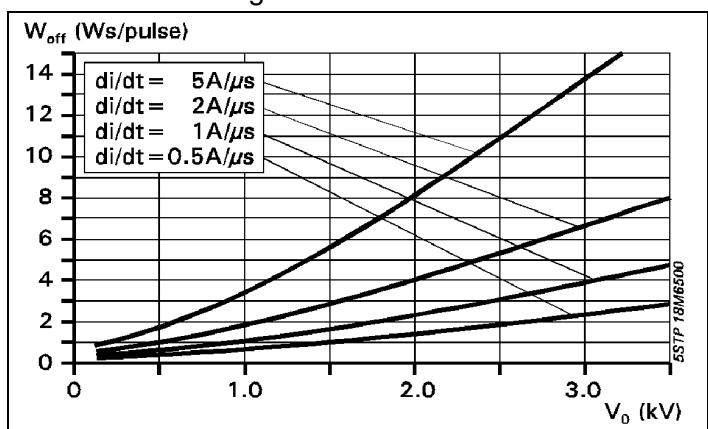
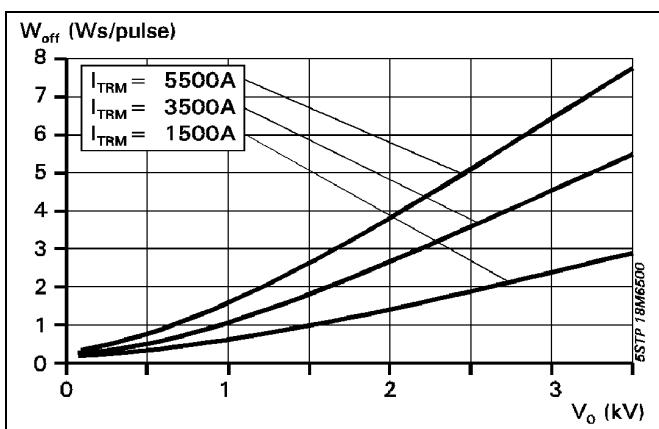
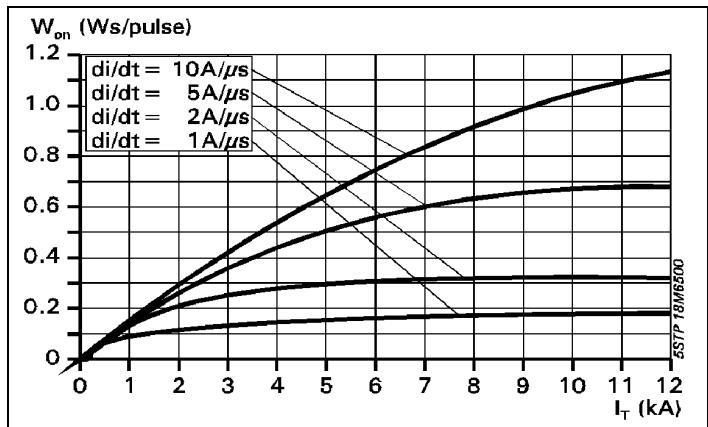
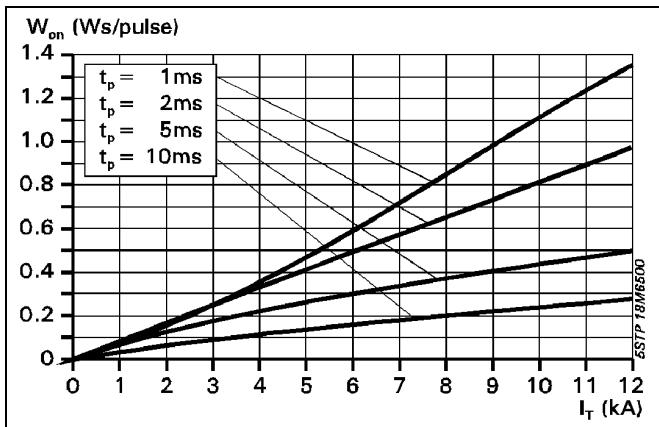


ABB Semiconductors reserves the right to change specifications without notice.



ABB Semiconductors AG
Fabrikstrasse 3
CH-5600 Lenzburg, Switzerland

Telephone +41 (0)62 888 6419
Fax +41 (0)62 888 6306
Email Info@ch.abb.com
Internet www.abbsem.com

Doc. No. 5SYA1010-03 Aug.00

